



LIST OF PUBLICATIONS CITED BY APPLICANT	<u>Atty. Docket No.</u> SEL 246		<u>Serial No.</u> 09/812,529			
	<u>Applicant</u> Koichiro TANAKA					
	<u>Filing Date</u> March 20, 2001		<u>Group</u> 2812			
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
NB	5,968,383	10/19/99	Yamazaki et al	219	121.75	10/23/97
	6,002,101	12/14/99	Yamazaki et al	219	121.75	10/23/97
	6,011,277	01/04/00	Yamazaki	257	66	09/09/98
	6,023,075	02/08/00	Yamazaki	257	72	10/31/97
	6,066,516	05/23/00	Miyasaka	438	149	01/31/97
	6,096,581	08/01/00	Zhang et al	438	149	05/02/96
	6,159,777	12/12/00	Takenouchi et al	438	149	10/28/97
	6,261,856 B1	07/17/01	Shinohara et al	438	30	12/10/98
	6,509,212 B1	01/21/03	Zhang et al	438	149	01/26/99
	6,528,397 B1	03/04/03	Taketomi et al	438	487	06/16/00
	NB	6,723,590 B1	04/20/04	Zhang et al	438	166
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	APPLICANT	English Abstract	English Trans.	FILING DATE
OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS (Include name of author (in CAPITAL LETTERS), title of article or item (book, magazine, journal, serial, symposium, catalog, etc.) date, pages(s), volume-issue number(s), publisher, city and/or country where published).						
EXAMINER: <i>Michael A. Booth</i>				DATE CONSIDERED: <i>08/20/04</i>		
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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
RB	4,330,363	05/18/82	Biegesen et al	156	620	08/28/80
	4,466,179	08/21/84	Kasten	29	576	10/19/82
	4,915,772	04/10/90	Fehlner et al	156	620	10/01/86
	5,145,808	09/08/92	Sameshima et al	437	173	08/20/91
	5,194,853	03/16/93	Asada	340	784	12/19/91
	5,247,375	09/21/93	Mochizuki et al	359	54	12/08/92
	5,264,383	11/23/93	Young	437	40	06/23/92
	5,365,875	11/22/94	Asai et al	117	7	09/18/92
	5,372,836	12/13/94	Imahashi et al	427	8	03/26/93
	5,403,762	04/04/95	Takemura	437	40	06/28/94
	5,403,772	04/04/95	Zhang et al	437	101	12/03/93
	5,413,958	05/09/95	Imahashi et al	437	173	11/16/93
	5,414,442	05/09/95	Yamazaki et al	345	89	06/12/92
	5,432,122	07/11/95	Chae	437	101	11/03/93
	5,449,637	09/12/95	Saito et al	437	57	09/27/93
	5,453,858	09/26/95	Yamazaki	359	59	02/03/95
	5,477,073	12/19/95	Wakai et al	257	347	08/09/94
	5,514,879	05/07/96	Yamazaki	257	65	06/07/95
	5,529,630	06/25/96	Imahashi et al	118	665	02/09/95
	5,529,937	06/25/96	Zhang et al	437	10	07/20/94
	5,561,081	10/01/96	Takenouchi et al	437	174	02/03/94
	5,563,426	10/08/96	Zhang et al	257	66	11/18/94
	5,565,377	10/15/96	Weiner et al	437	173	10/27/94
	5,570,105	10/29/96	Koyama	345	98	12/21/94
	5,614,732	03/25/97	Yamazaki	257	66	08/19/94
	5,680,147	10/21/97	Yamazaki et al	345	94	05/19/92
	5,701,167	12/23/97	Yamazaki	349	42	09/13/96
	5,708,252	01/13/98	Shinohara et al	219	121.73	01/22/96
	5,767,930	06/16/98	Kobayashi et al	349	42	05/20/97
	5,849,601	12/15/98	Yamazaki	437	101	04/22/94
	5,858,473	01/12/99	Yamazaki et al	427	554	09/06/96
	5,859,445	01/12/99	Yamazaki	257	66	02/14/97
	5,897,799	04/27/99	Yamazaki et al	219	121.75	06/11/96
	5,939,731	08/17/99	Yamazaki et al	257	59	01/08/97
	5,943,593	08/24/99	Noquchi et al	438	487	05/22/98

Richard A. Booth

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### FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	APPLICANT	English Abstract	English Trans.	FILING DATE
NB	JP 58-127318	07/29/83	Nippon Telegraph & Telephone Corp.	X		01/25/82
	JP 59-161014	09/11/84	Seiko Instrument & Electronics Ltd.	X		03/03/83
	EP 0 091 806	10/19/83	Fujitsu Ltd.			04/08/83
	JP 02-042717	02/13/90	Hitachi Ltd.	X		08/03/88
	JP 03-280531	12/11/91	Fuotokusu KK	X		03/29/90
	JP 04-242724	08/31/92	Semiconductor Energy Lab Co. Ltd		X	12/25/90
	JP 04-282869	10/07/92	GTC KK	X		03/11/91
	JP 05-040278	02/19/93	NEC Corp.	X		08/06/91
	JP 05-175235	07/13/93	Sharp Corp.	X		12/25/91
	JP 05-203977	08/13/93	Seiko Epson Corp.	X		08/28/92
	JP 05-211167	08/20/93	NEC Corp.	X		11/29/91
	JP 05-251342	09/28/93	Semiconductor Energy Lab Co. Ltd	X		12/04/92
	JP 06-045272	02/18/94	Hitachi Ltd.	X		07/21/92
	JP 06-059278	03/04/94	Hitachi Ltd.	X		08/07/92
	JP 06-260502	09/16/94	Seiko Epson Corp.	X		03/04/93
	JP 07-307304	11/21/95	Semiconductor Energy Lab Co. Ltd	X		05/13/94

### OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

(Include name of author (in CAPITAL LETTERS), title of article or item (book, magazine, journal, serial, symposium, catalog, etc.) date, pages(s), volume-issue number(s), publisher, city and/or country where published).

NB	1) FUJIEDA, I. et al, "Self-Referenced Poly-Si TFT Amplifier Readout for a Linear Image Sensor," IDEM 93, pp. 587-590, (1993).
	2) BONNEL, M. et al, "Polycrystalline Silicon Thin-Film Transistors with Two-Step Annealing Process," IEEE Electron Device Letters, vol. 14, no. 12, pp. 551-553, December, (1993).
	3) FUSE, M. et al, "Performance of Poly-Si Thin Film Transistors Fabricated by Excimer-Laser Annealing of SiH <sub>4</sub> and Si <sub>2</sub> H <sub>6</sub> Source Low Pressure Vapor Deposited a-Si Films With or Without Solid-Phase Crystallization," Solid State Phenomena, vols. 37-38, pp. 565-570 (1994).
	4) Webster's II New Riverside University Dictionary, (1994).

EXAMINER:

*Richard A. [Signature]*

DATE CONSIDERED:

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